

CD74HC4094, CD74HCT4094

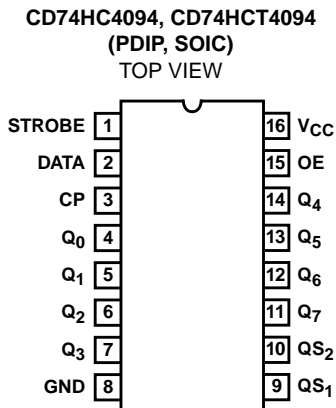
High Speed CMOS Logic 8-Stage Shift and Store Bus Register, Three-State

November 1997

Features

- Buffered Inputs
- Separate Serial Outputs Synchronous to Both Positive and Negative Clock Edges For Cascading
- Fanout (Over Temperature Range)
 - Standard Outputs 10 LSTTL Loads
 - Bus Driver Outputs 15 LSTTL Loads
- Wide Operating Temperature Range . . . -55°C to 125°C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- HC Types
 - 2V to 6V Operation
 - High Noise Immunity: $N_{IL} = 30\%$, $N_{IH} = 30\%$ of V_{CC} at $V_{CC} = 5V$
- HCT Types
 - 4.5V to 5.5V Operation
 - Direct LSTTL Input Logic Compatibility, $V_{IL} = 0.8V$ (Max), $V_{IH} = 2V$ (Min)
 - CMOS Input Compatibility, $I_I \leq 1\mu A$ at V_{OL} , V_{OH}

Pinout



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Description

The Harris CD74HC4094 and CD74HCT4094 are 8-stage serial shift registers having a storage latch associated with each stage for strobing data from the serial input to parallel buffered three-state outputs. The parallel outputs may be connected directly to common bus lines. Data is shifted on positive clock transitions. The data in each shift register stage is transferred to the storage register when the Strobe input is high. Data in the storage register appears at the outputs whenever the Output-Enable signal is high.

Two serial outputs are available for cascading a number of these devices. Data is available at the QS₁ serial output terminal on positive clock edges to allow for high-speed operation in cascaded system in which the clock rise time is fast. The same serial information, available at the QS₂ terminal on the next negative clock edge, provides a means

for cascading these devices when the clock rise time is slow.

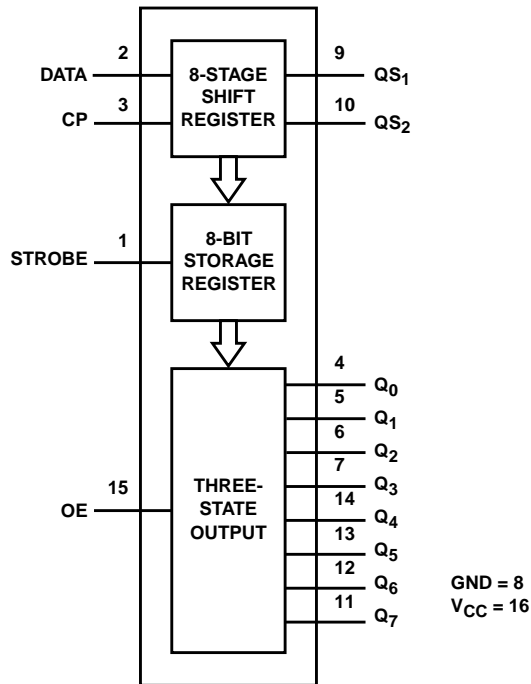
Ordering Information

PART NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. NO.
CD74HC4094E	-55 to 125	16 Ld PDIP	E16.3
CD74HCT4094E	-55 to 125	16 Ld PDIP	E16.3
CD74HC4094M	-55 to 125	16 Ld SOIC	M16.15
CD74HCT4094M	-55 to 125	16 Ld SOIC	M16.15

NOTES:

1. When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.
2. Wafer or die for this part number is available which meets all electrical specifications. Please contact your local sales office or Harris customer service for ordering information.

Functional Diagram



TRUTH TABLE

INPUTS				PARALLEL OUTPUTS		SERIAL OUTPUTS	
CP	OE	STR	D	Q ₀	Q _n	QS ₁ (NOTE 4)	QS ₂
↑	L	X	X	Z	Z	Q'6	NC
↓	L	X	X	Z	Z	NC	Q ₇
↑	H	L	X	NC	NC	Q'6	NC
↑	H	H	L	L	Q _n -1	Q'6	NC

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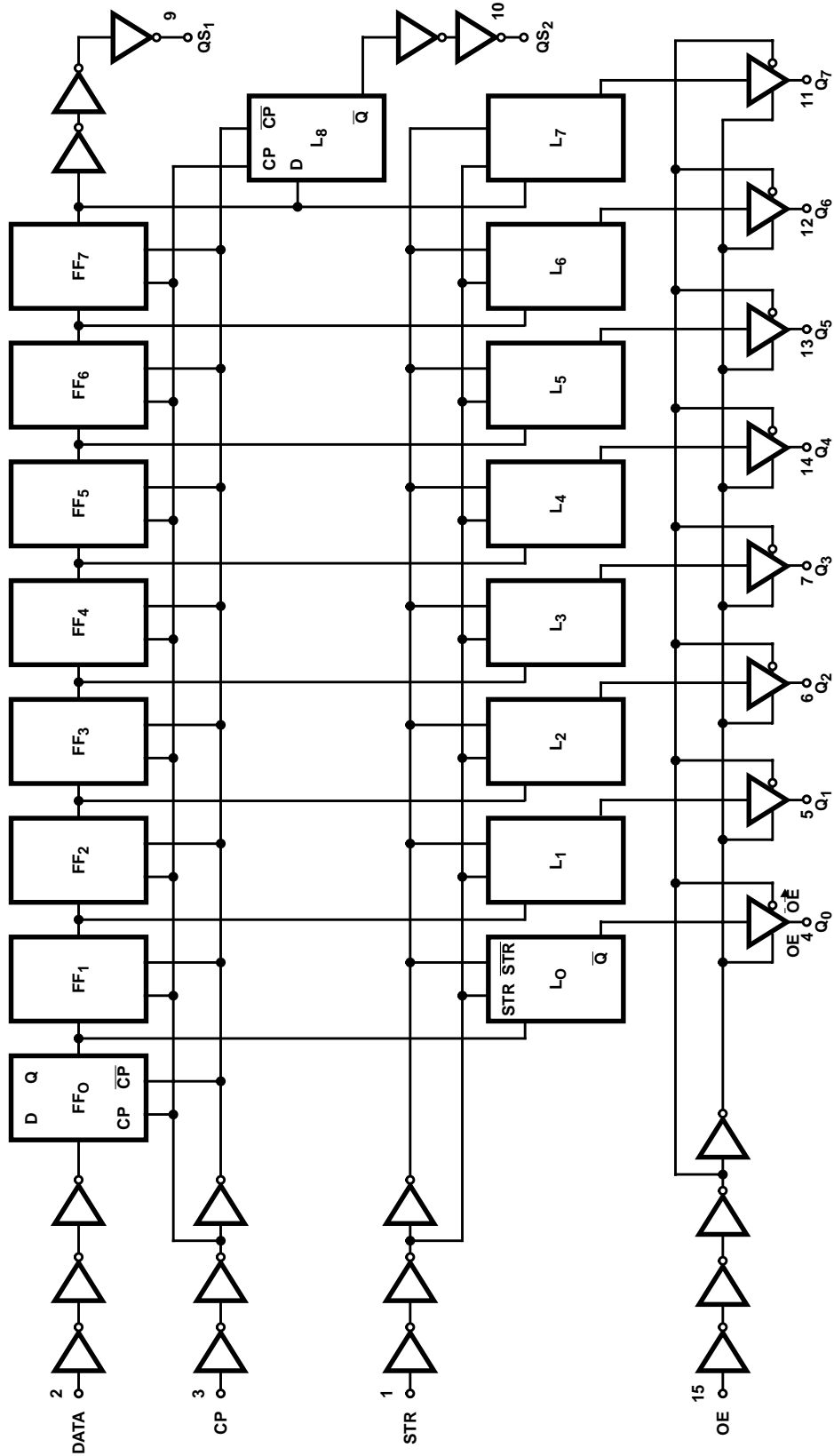
TRUTH TABLE

INPUTS				PARALLEL OUTPUTS		SERIAL OUTPUTS	
CP	OE	STR	D	Q ₀	Q _n	QS ₁ (NOTE 4)	QS ₂
↑	H	H	H	H	Q _n -1	Q'6	NC
↓	H	H	H	NC	NC	NC	Q ₇

NOTES:

3. H = High Voltage Level, L = Low Voltage Level, X = Don't Care, NC = No charge, Z = High Impedance Off-state,
↑ = Transition from Low to High Level, ↓ = Transition from High to Low.
4. At the positive clock edge the information in the seventh register stage is transferred to the 8th register stage and QS₁ output.

Logic Diagram



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Absolute Maximum Ratings

DC Supply Voltage, V_{CC}	-0.5V to 7V
DC Input Diode Current, I_{IK}	
For $V_I < -0.5V$ or $V_I > V_{CC} + 0.5V$	$\pm 20mA$
DC Output Diode Current, I_{OK}	
For $V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$	$\pm 20mA$
DC Output Source or Sink Current per Output Pin, I_O	
For $V_O > -0.5V$ or $V_O < V_{CC} + 0.5V$	$\pm 25mA$
DC V_{CC} or Ground Current, I_{CC}	$\pm 50mA$

Thermal Information

Thermal Resistance (Typical, Note 5)	θ_{JA} (°C/W)
PDIP Package	90
SOIC Package	160
Maximum Junction Temperature	150°C
Maximum Storage Temperature Range	-65°C to 150°C
Maximum Lead Temperature (Soldering 10s)	300°C (SOIC - Lead Tips Only)

Operating Conditions

Temperature Range (T_A)	-55°C to 125°C
Supply Voltage Range, V_{CC}	
HC Types2V to 6V
HCT Types4.5V to 5.5V
DC Input or Output Voltage, V_I, V_O	0V to V_{CC}
Input Rise and Fall Time	
2V	1000ns (Max)
4.5V	500ns (Max)
6V	400ns (Max)

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

5. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

DC Electrical Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS	
		V_I (V)	I_O (mA)		MIN	TYP	MAX	MIN	MAX	MIN	MAX		
HC TYPES													
High Level Input Voltage	V_{IH}	-	-	2	1.5	-	-	1.5	-	1.5	-	V	
				4.5	3.15	-	-	3.15	-	3.15	-	V	
				6	4.2	-	-	4.2	-	4.2	-	V	
Low Level Input Voltage	V_{IL}	-	-	2	-	-	0.5	-	0.5	-	0.5	V	
				4.5	-	-	1.35	-	1.35	-	1.35	V	
				6	-	-	1.8	-	1.8	-	1.8	V	
High Level Output Voltage CMOS Loads	V_{OH}	V_{IH} or V_{IL}	-0.02	2	1.9	-	-	1.9	-	1.9	-	V	
				4.5	4.4	-	-	4.4	-	4.4	-	V	
				6	5.9	-	-	5.9	-	5.9	-	V	
High Level Output Voltage TTL Loads	V_{OH}	V_{IH} or V_{IL}	-	-	-	-	-	-	-	-	-	V	
				-4	4.5	3.98	-	-	3.84	-	3.7	-	V
				-5.2	6	5.48	-	-	5.34	-	5.2	-	V
Low Level Output Voltage CMOS Loads	V_{OL}	V_{IH} or V_{IL}	0.02	2	-	-	0.1	-	0.1	-	0.1	V	
				4.5	-	-	0.1	-	0.1	-	0.1	V	
				6	-	-	0.1	-	0.1	-	0.1	V	
Low Level Output Voltage TTL Loads	V_{OL}	V_{IH} or V_{IL}	-	-	-	-	-	-	-	-	-	V	
				4	4.5	-	-	0.26	-	0.33	-	0.4	V
				5.2	6	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I_I	V_{CC} or GND	-	6	-	-	± 0.1	-	± 1	-	± 1	μA	
Quiescent Device Current	I_{CC}	V_{CC} or GND	0	6	-	-	8	-	80	-	160	μA	

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DC Electrical Specifications (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS		V _{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
		V _I (V)	I _O (mA)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HCT TYPES												
High Level Input Voltage	V _{IH}	-	-	4.5 to 5.5	2	-	-	2	-	2	-	V
Low Level Input Voltage	V _{IL}	-	-	4.5 to 5.5	-	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage CMOS Loads	V _{OH}	V _{IH} or V _{IL}	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
High Level Output Voltage TTL Loads			-4	4.5	3.98	-	-	3.84	-	3.7	-	V
Low Level Output Voltage CMOS Loads	V _{OL}	V _{IH} or V _{IL}	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			4	4.5	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I _I	V _{CC} and GND	0	5.5	-	-	±0.1	-	±1	-	±1	μA
Quiescent Device Current	I _{CC}	V _{CC} or GND	0	5.5	-	-	8	-	80	-	160	μA
Additional Quiescent Device Current Per Input Pin: 1 Unit Load	ΔI _{CC} (Note)	V _{CC} -2.1	-	4.5 to 5.5	-	100	360	-	450	-	490	μA

NOTE: For dual-supply systems theoretical worst case (V_I = 2.4V, V_{CC} = 5.5V) specification is 1.8mA.

HCT Input Loading Table

INPUT	UNIT LOADS
D	0.4
CP, OE	1.5
STR	1.0

NOTE: Unit Load is ΔI_{CC} limit specified in DC Electrical Table, e.g., 360μA max at 25°C.

Prerequisite for Switching Specifications

CHARACTERISTIC	SYMBOL	V _{CC} (V)	25°C		-40°C TO 85°C		-55°C TO 125°C		UNITS
			MIN	MAX	MIN	MAX	MIN	MAX	
HC TYPES									
CP Pulse Width	t _w	2	80	-	100	-	120	-	ns
		4.5	16	-	20	-	24	-	ns
		6	14	-	17	-	20	-	ns
STR Pulse Width	t _{WH}	2	80	-	100	-	120	-	ns
		4.5	16	-	20	-	24	-	ns
		6	14	-	17	-	20	-	ns

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Prerequisite for Switching Specifications (Continued)

CHARACTERISTIC	SYMBOL	V _{CC} (V)	25°C		-40°C TO 85°C		-55°C TO 125°C		UNITS
			MIN	MAX	MIN	MAX	MIN	MAX	
Data Set-up Time	t _{SU}	2	50	-	65	-	75	-	ns
		4.5	10	-	13	-	15	-	ns
		6	9	-	11	-	13	-	ns
Data Hold Time	t _H	2	3	-	3	-	3	-	ns
		4.5	3	-	3	-	3	-	ns
		6	3	-	3	-	3	-	ns
STR Set-up Time	t _{SU}	2	100	-	125	-	150	-	ns
		4.5	20	-	25	-	30	-	ns
		6	17	-	21	-	26	-	ns
STR Hold Time	t _H	2	0	-	0	-	0	-	ns
		4.5	0	-	0	-	0	-	ns
		6	0	-	0	-	0	-	ns
Maximum CP Frequency	f _{CL} (MAX)	2	6	-	5	-	4	-	MHz
		4.5	30	-	24	-	20	-	MHz
		6	35	-	28	-	24	-	MHz

HCT TYPES

CP Pulse Width	t _W	4.5	16	-	20	-	24	-	ns
STR Pulse Width	t _{WH}	4.5	16	-	20	-	24	-	ns
Data Set-up Time	t _{SU}	4.5	10	-	13	-	15	-	ns
Data Hold Time	t _H	4.5	4	-	4	-	4	-	ns
STR Set-up Time	t _{SU}	4.5	20	-	25	-	30	-	ns
STR Hold Time	t _H	4.5	0	-	0	-	0	-	ns
Maximum CP Frequency	f _{CL} (MAX)	4.5	30	-	24	-	20	-	MHz

Switching Specifications Input t_r, t_f = 6ns

PARAMETER	SYMBOL	TEST CONDITIONS	V _{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES											
Propagation Delay Time (Figure 1) CP to QS ₁	t _{PLH} , t _{PHL}	C _L = 50pF	2	-	-	150	-	190	-	225	ns
			4.5	-	-	30	-	38	-	45	ns
		C _L = 15pF	5	-	12	-	-	-	-	-	ns
			C _L = 50pF	6	-	-	26	-	33	-	38
CP to QS ₂	t _{PLH} , t _{PHL}	C _L = 50pF	2	-	-	135	-	170	-	205	ns
			4.5	-	-	27	-	34	-	41	ns
		C _L = 15pF	5	-	11	-	-	-	-	-	ns
			C _L = 50pF	6	-	-	23	-	29	-	35
CP to Q _n	t _{PLH} , t _{PHL}	C _L = 50pF	2	-	-	195	-	245	-	295	ns
			4.5	-	-	39	-	49	-	59	ns
			5	-	16	-	-	-	-	-	ns
			6	-	-	33	-	42	-	50	ns
STR to Q _n	t _{PLH} , t _{PHL}	C _L = 50pF	2	-	-	180	-	225	-	270	ns
			4.5	-	-	36	-	45	-	54	ns
			6	-	-	31	-	38	-	46	ns

Switching Specifications Input t_r , $t_f = 6\text{ns}$ (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS	V_{CC} (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
Output Enable to Q_n	t_{PZH}, t_{PZL}	$C_L = 50\text{pF}$	2	-	-	175	-	220	-	265	ns
			4.5	-	-	35	-	44	-	53	ns
			6	-	-	30	-	37	-	45	ns
Output Disable to Q_n	t_{PHZ}, t_{PLZ}	$C_L = 50\text{pF}$	2	-	-	125	-	155	-	190	ns
			4.5	-	-	25	-	31	-	38	ns
			6	-	-	21	-	26	-	32	ns
Output Transition Time	t_{TLH}, t_{THL}	$C_L = 50\text{pF}$	2	-	-	75	-	95	-	110	ns
			4.5	-	-	15	-	19	-	22	ns
			6	-	-	13	-	16	-	19	ns
Output Disabling Time	t_{PHZ}, t_{PLZ}	$C_L = 15\text{pF}$	5	-	10	-	-	-	-	ns	
Maximum CP Frequency	f_{MAX}	$C_L = 15\text{pF}$	5	-	60	-	-	-	-	MHz	
Input Capacitance	C_{IN}	$C_L = 50\text{pF}$	-	-	-	10	-	10	-	10	pF
Power Dissipation Capacitance (Notes 6, 7)	C_{PD}	$C_L = 15\text{pF}$	5	-	90	-	-	-	-	-	pF
Three-State Output Capacitance	C_O	$C_L = 50\text{pF}$	-	-	-	15	-	15	-	15	pF
HCT TYPES											
Propagation Delay Time (Figure 1)	t_{PLH}, t_{PHL}	$C_L = 50\text{pF}$	4.5	-	-	39	-	-	-	-	ns
		$C_L = 15\text{pF}$	5	-	16	-	-	-	-	-	ns
CP to QS_2	t_{PLH}, t_{PHL}	$C_L = 50\text{pF}$	4.5	-	-	36	-	-	-	-	ns
		$C_L = 15\text{pF}$	5	-	15	-	-	-	-	-	ns
CP to Q_n	t_{PLH}, t_{PHL}	$C_L = 50\text{pF}$	4.5	-	-	43	-	-	-	-	ns
		$C_L = 15\text{pF}$	5	-	18	-	-	-	-	-	ns
STR to Q_n	t_{PLH}, t_{PHL}	$C_L = 50\text{pF}$	4.5	-	-	39	-	-	-	-	ns
Output Enable to Q_n	t_{PZH}, t_{PZL}	$C_L = 50\text{pF}$	4.5	-	-	35	-	-	-	-	ns
Output Disable to Q_n	t_{PHZ}, t_{PLZ}	$C_L = 50\text{pF}$	4.5	-	-	35	-	-	-	-	ns
Output Transition Time	t_{TLH}, t_{THL}	$C_L = 50\text{pF}$	4.5	-	-	15	-	-	-	-	ns
Output Disabling Time	t_{PHZ}, t_{PLZ}	$C_L = 15\text{pF}$	5	-	14	-	-	-	-	-	ns
Maximum CP Frequency	f_{MAX}	$C_L = 15\text{pF}$	5	-	60	-	-	-	-	-	MHz
Input Capacitance	C_{IN}	$C_L = 50\text{pF}$	-	-	-	10	-	10	-	10	pF
Power Dissipation Capacitance (Notes 6, 7)	C_{PD}	$C_L = 15\text{pF}$	5	-	110	-	-	-	-	-	pF
Three-State Output Capacitance	C_O	$C_L = 50\text{pF}$	-	-	-	15	-	15	-	15	pF

NOTES:

- C_{PD} is used to determine the dynamic power consumption, per register.
- $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$ where f_i = Input Frequency, C_L = Output Load Capacitance, V_{CC} = Supply Voltage.

Test Circuits and Waveforms

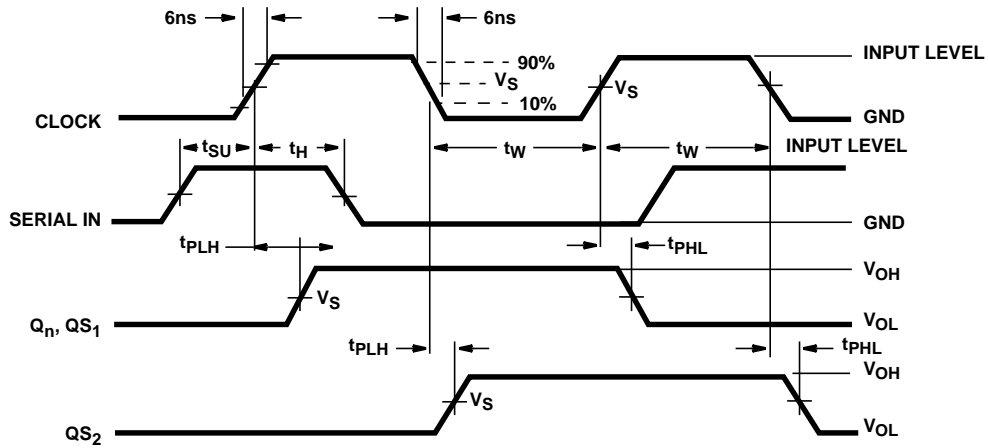


FIGURE 1. DATA PROPAGATION DELAYS, SET-UP AND HOLD TIMES

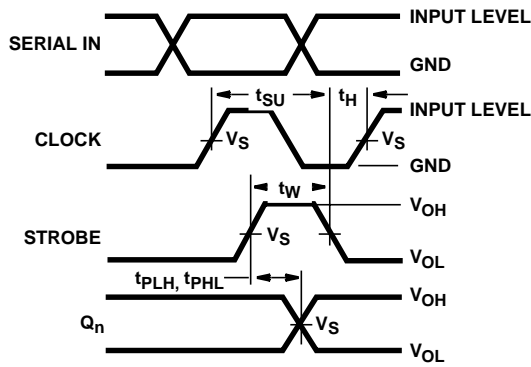


FIGURE 2. STROBE PROPAGATION DELAYS AND SET-UP AND HOLD TIMES

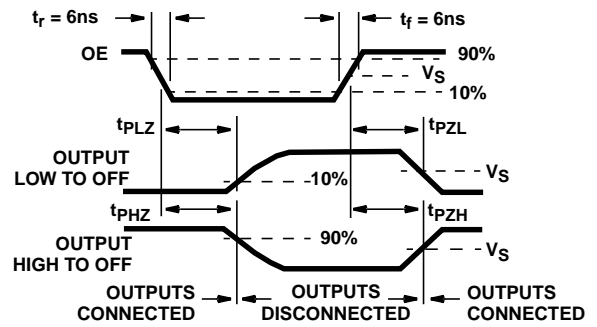


FIGURE 3. ENABLE AND DISABLE TIMES

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